

FQD2N90-VB Datasheet

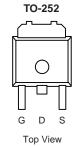
N-Channel 900 V (D-S) Super Junction Power MOSFET

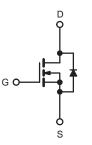
PRODUCT SUMMARY						
V _{DS} (V)	900	900				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	2.7				
Q _g (Max.) (nC)	200	200				
Q _{gs} (nC)	24	24				
Q _{gd} (nC)	110	110				
Configuration	Sing	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	900	V	
Gate-Source Voltage			V _{GS}	± 20	7 v	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	- 1	2.0		
Continuous Drain Current	VGS at 10 V	T _C = 100 °C	I _D	1.5	Α	
Pulsed Drain Current ^a			I _{DM}	8.0		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	470	mJ	
Repetitive Avalanche Current ^a			I _{AR}	4.8	Α	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P _D	120	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d	7	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=23~mH, $R_g=25~\Omega$, $I_{AS}=7.8~A$ (see fig. 12). c. $I_{SD}\leq 7.8~A$, $dI/dt\leq 140~A/\mu s$, $V_{DD}\leq 600~V$, $T_J\leq 150~^{\circ}C$. d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		900	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 800 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	100 500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}		I _D = 1.7 A ^b	_	2.7	-	Ω
Forward Transconductance	9fs		= 100 V, I _D = 1.7 A ^b	5.6	-	-	S
Dynamic	<u> </u>		_	L		1	
Input Capacitance	C _{iss}	V 0V		-	1800	-	
Output Capacitance	C _{oss}	1	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$	-	500	-	рF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	290	-	•
Total Gate Charge	Qg			-	-	200	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 1.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	24	
Gate-Drain Charge	Q_{gd}	See lig. 6 and 13		-	-	110	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 400 V, I_{D} = 1.8 A, R_{g} = 6.2 Ω , R_{D} = 52 Ω see fig. 10 ^b		-	19	-	- ns
Rise Time	t _r			-	38	-	
Turn-Off Delay Time	$t_{d(off)}$			-	120	-	
Fall Time	t _f			-	39	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	- N.I.
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 1.8 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 1.8 A, dl/dt = 100 A/μs ^b		-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Fig. 1 - Typical Output Characteristics, T_C = 25 °C



Fig. 2 - Typical Output Characteristics, T_C = 150 °C

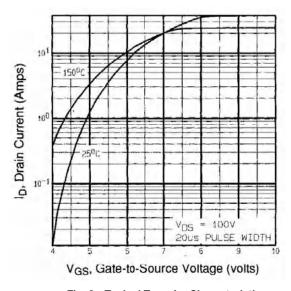


Fig. 3 - Typical Transfer Characteristics

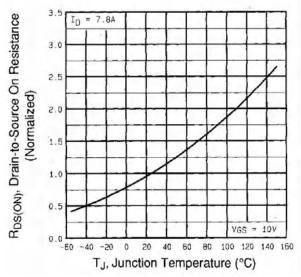


Fig. 4 - Normalized On-Resistance vs. Temperature



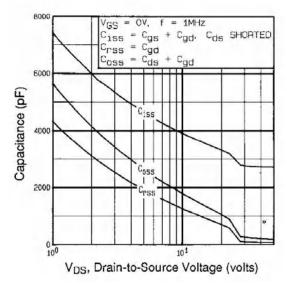


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

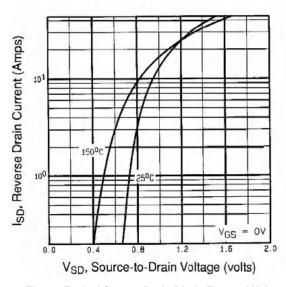


Fig. 7 - Typical Source-Drain Diode Forward Voltage

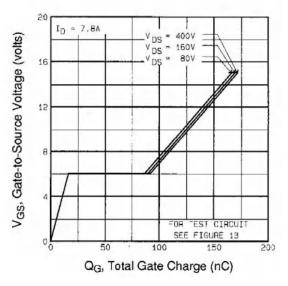


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

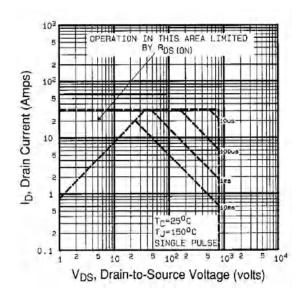


Fig. 8 - Maximum Safe Operating Area



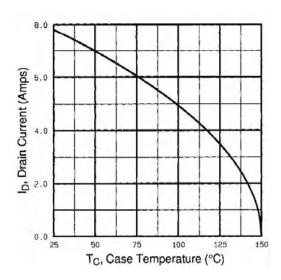


Fig. 9 - Maximum Drain Current vs. Case Temperature

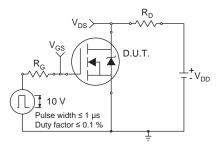


Fig. 10a - Switching Time Test Circuit

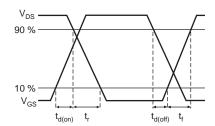


Fig. 10b - Switching Time Waveforms

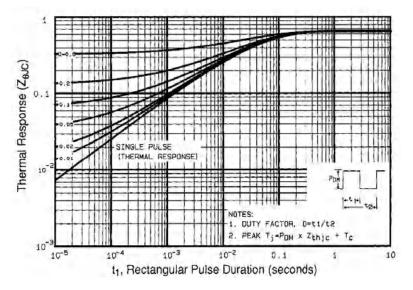


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



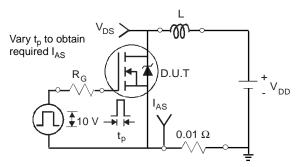


Fig. 12a - Unclamped Inductive Test Circuit

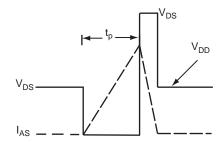


Fig. 12b - Unclamped Inductive Waveforms

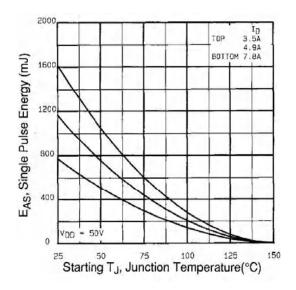


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

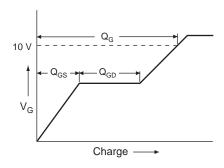


Fig. 13a - Basic Gate Charge Waveform

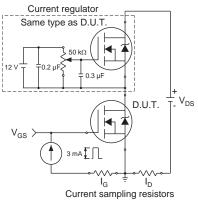
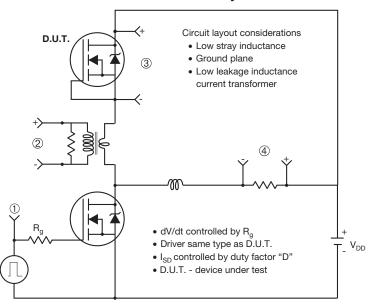


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit



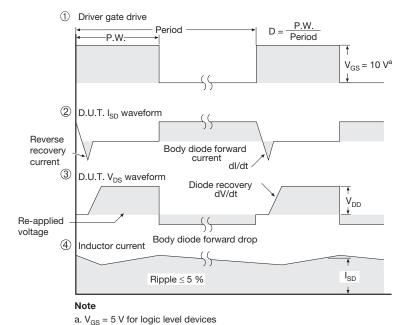
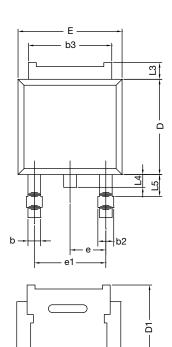
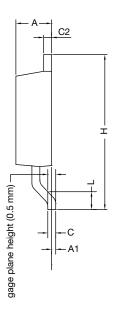


Fig. 14 - For N-Channel



TO-252AA CASE OUTLINE





	MILLIN	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	2.18	2.38	0.086	0.094	
A1	=	0.127	=	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	=	0.205	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	=	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	=	1.02	=	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347					

Note

• Dimension L3 is for reference only.



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